

Figure 2A

X-Ray Photoelectron Deffraction Graph
of a Si Substrate and SiGeC Layers with
Different C Concentrations

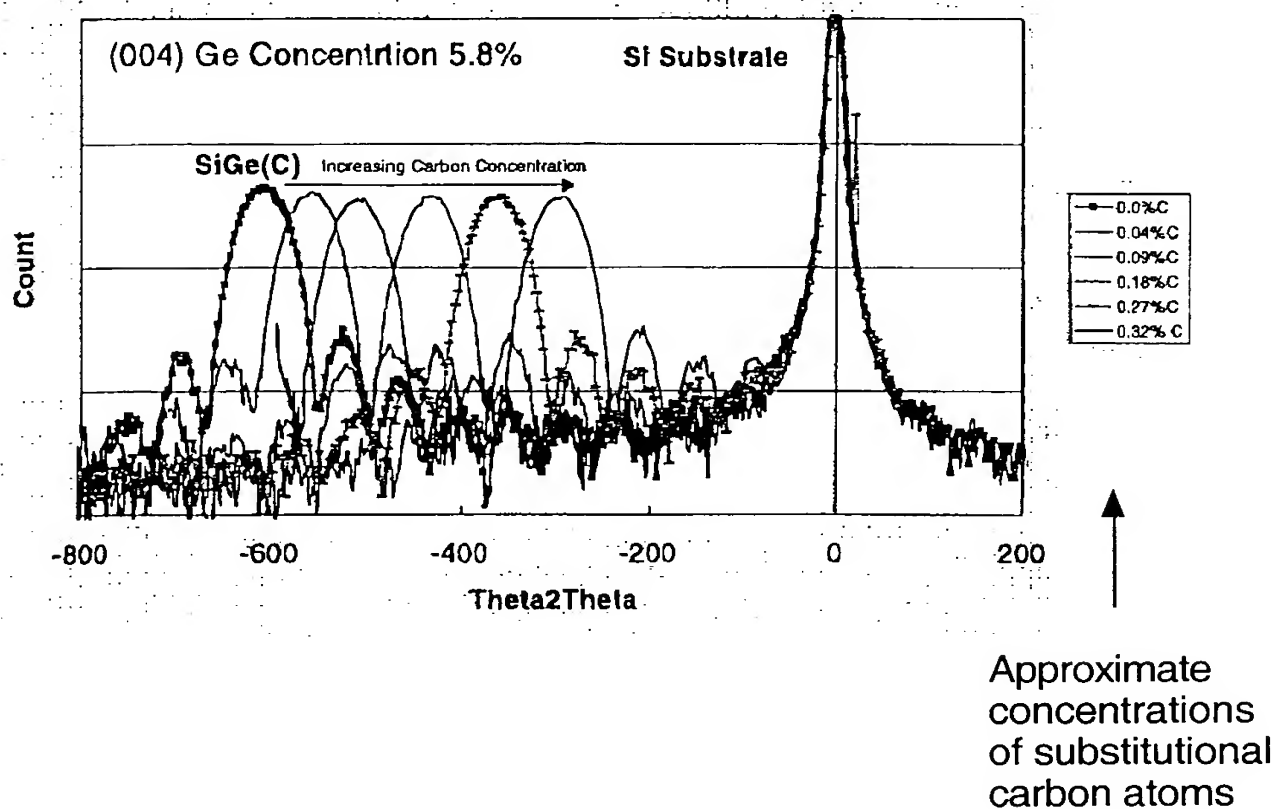


Figure 2B

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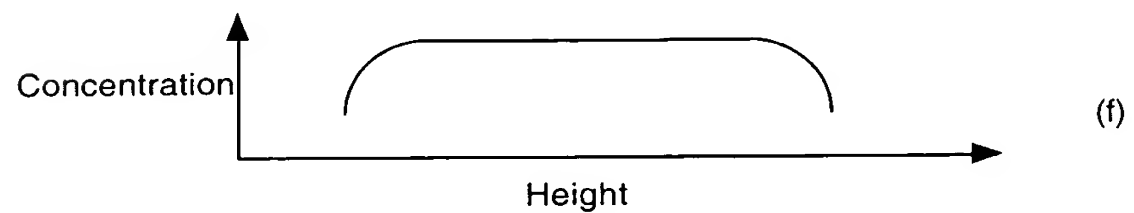
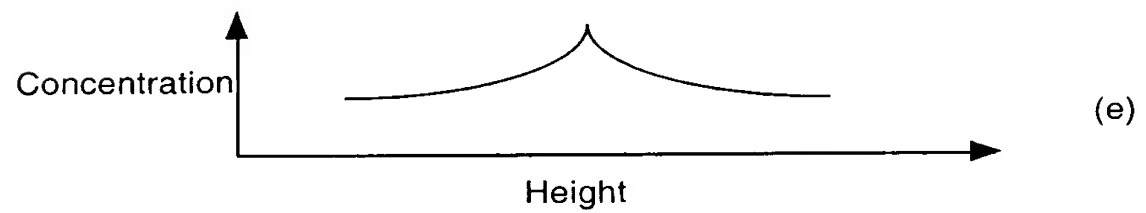
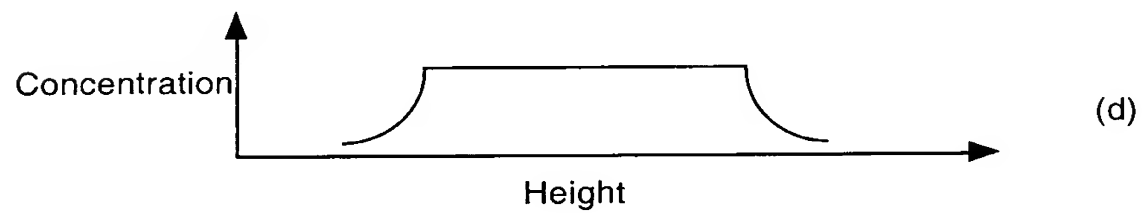
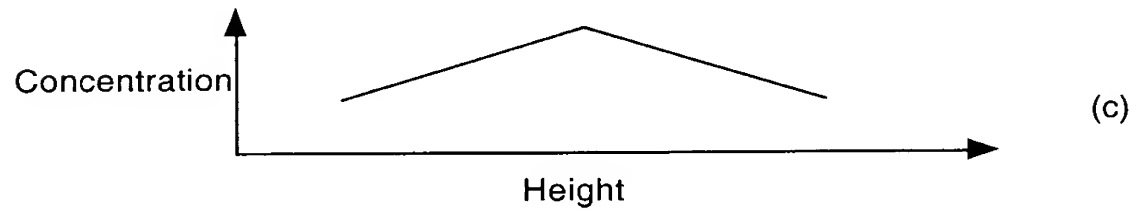
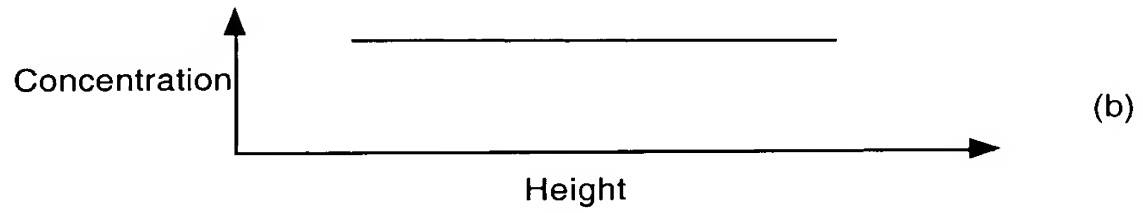
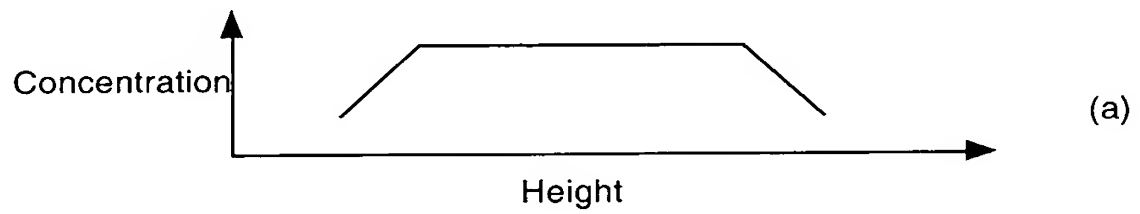
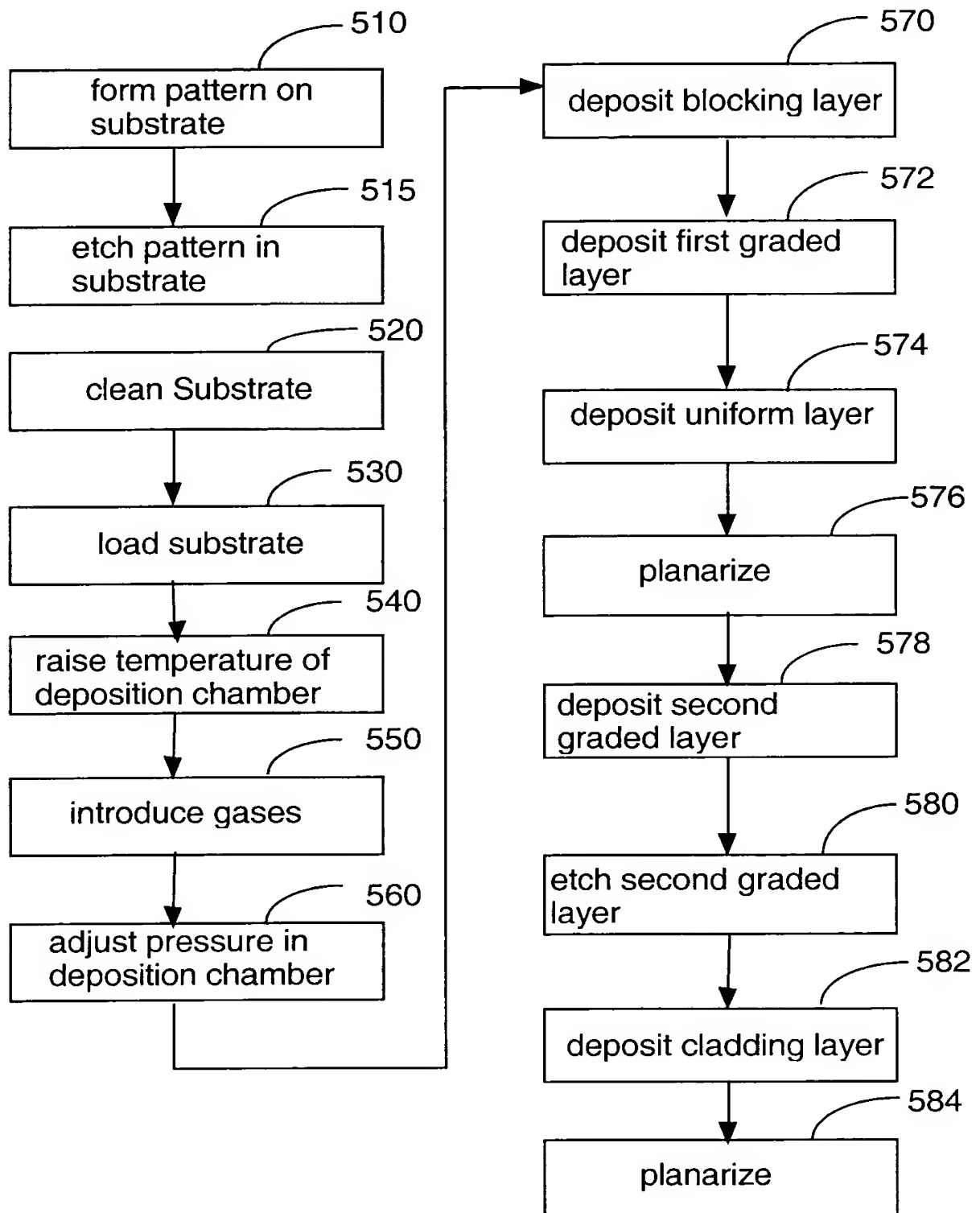
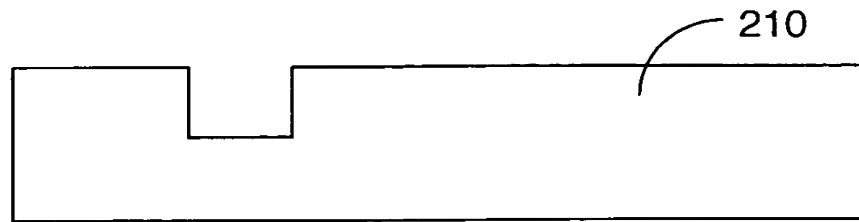


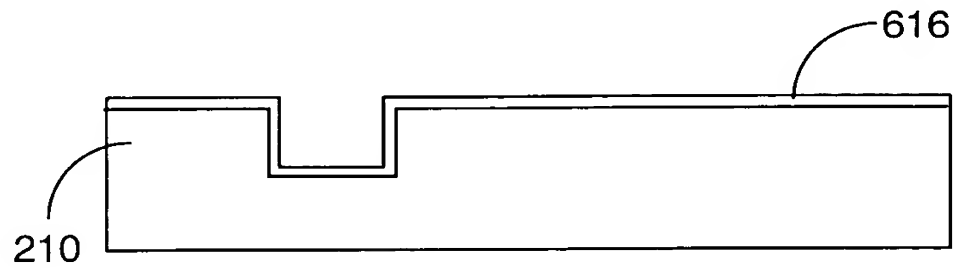
Figure 3

**Figure 4**

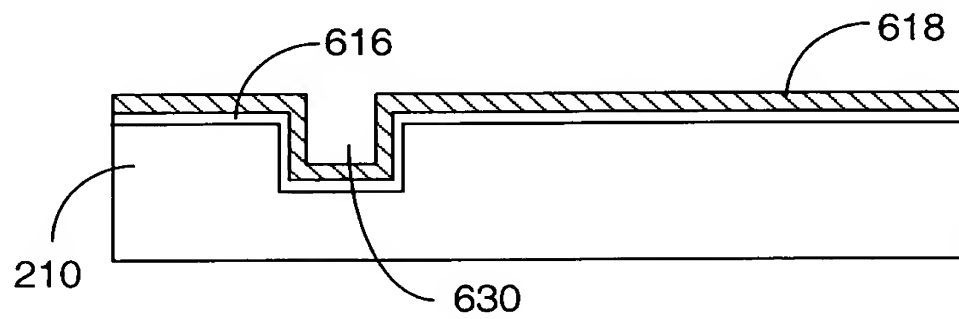
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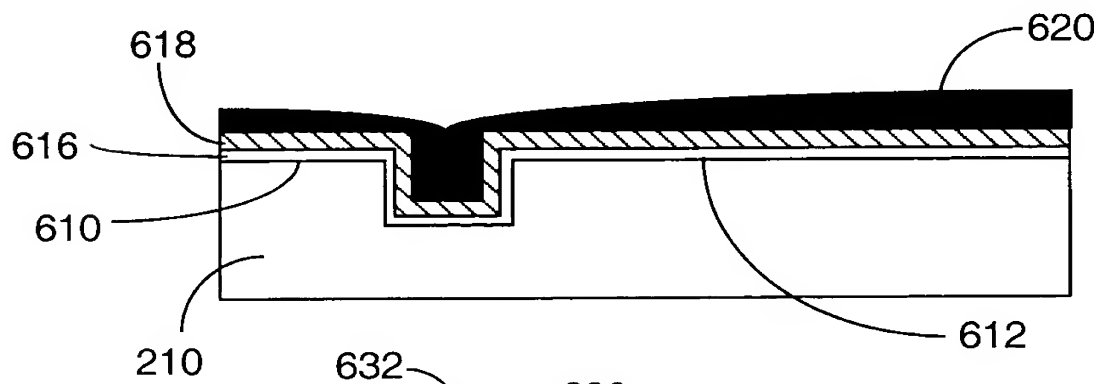
(a)



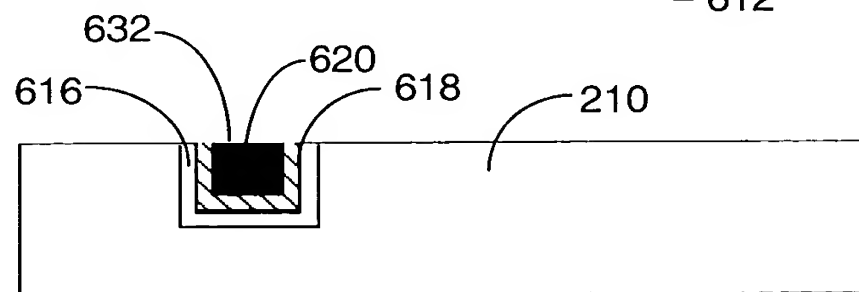
(b)



(c)



(d)



(e)

Figure 5

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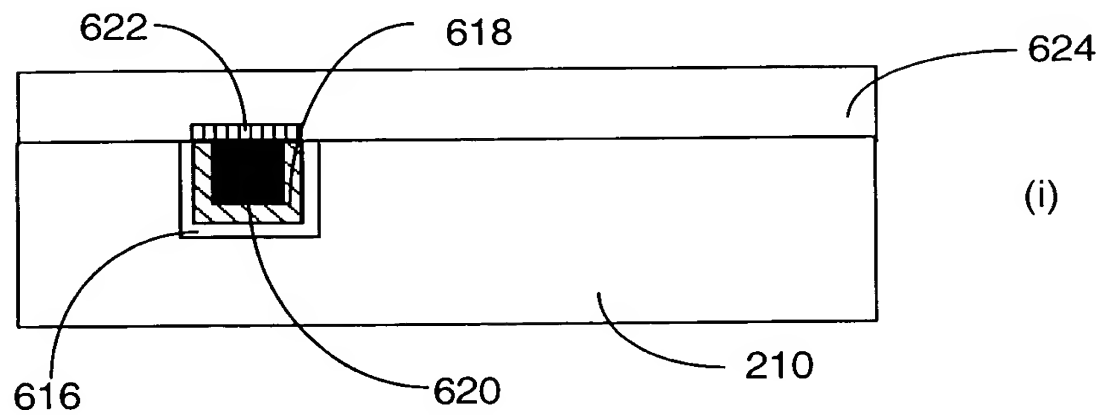
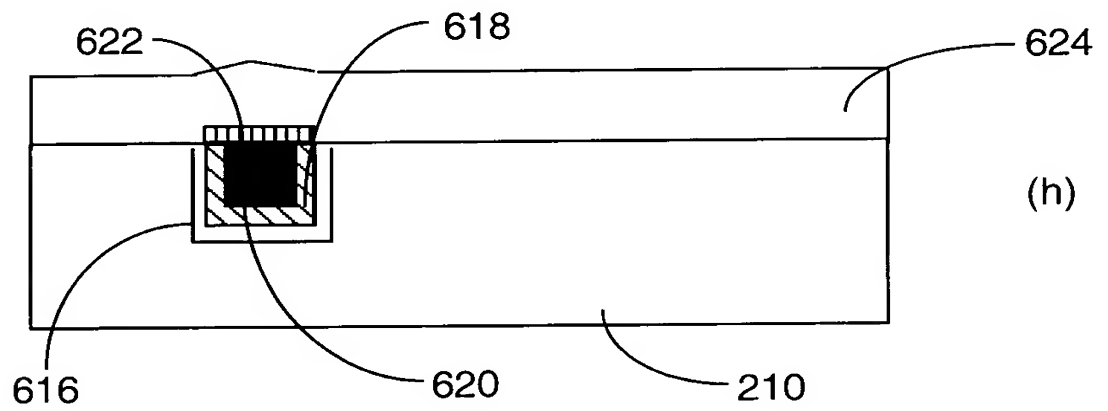
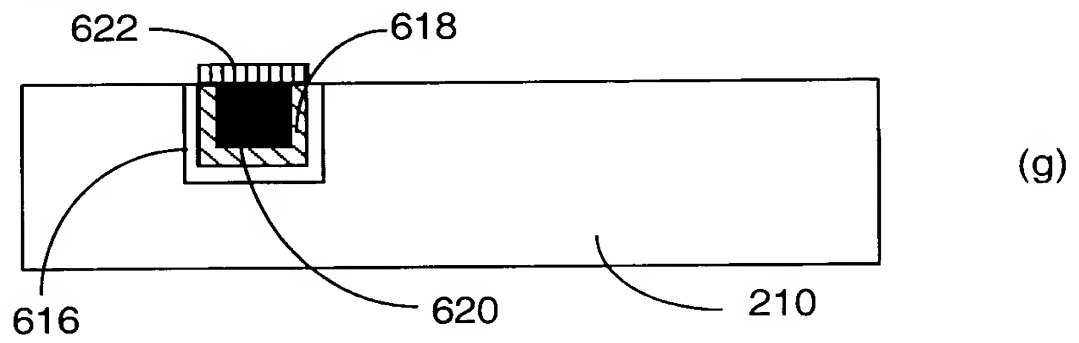
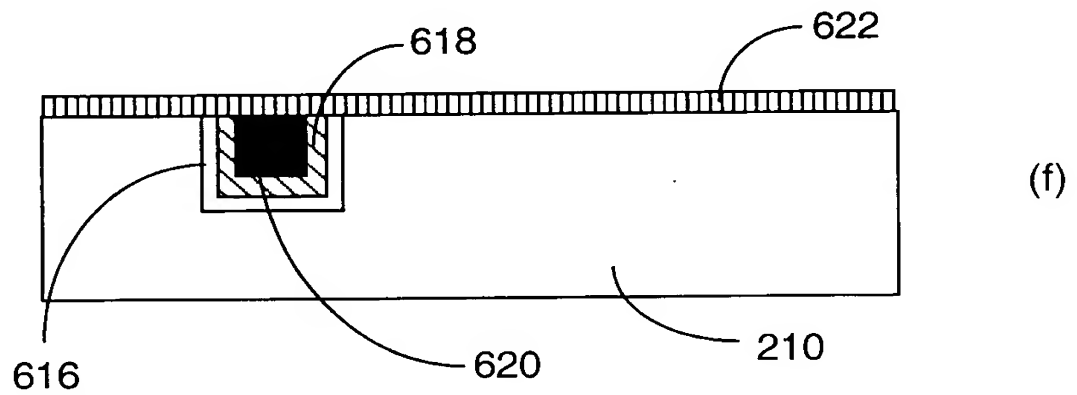


Figure 5

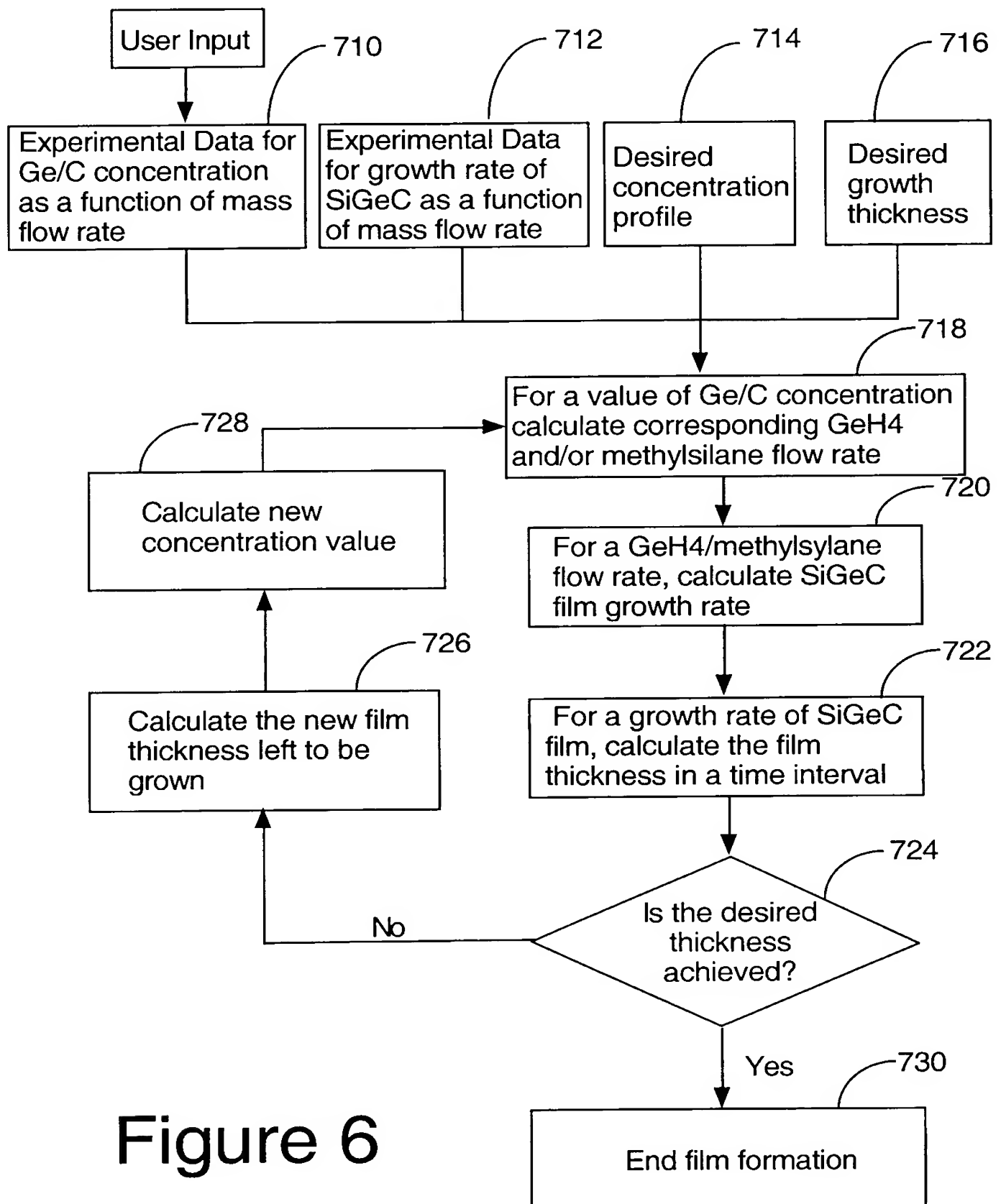


Figure 6

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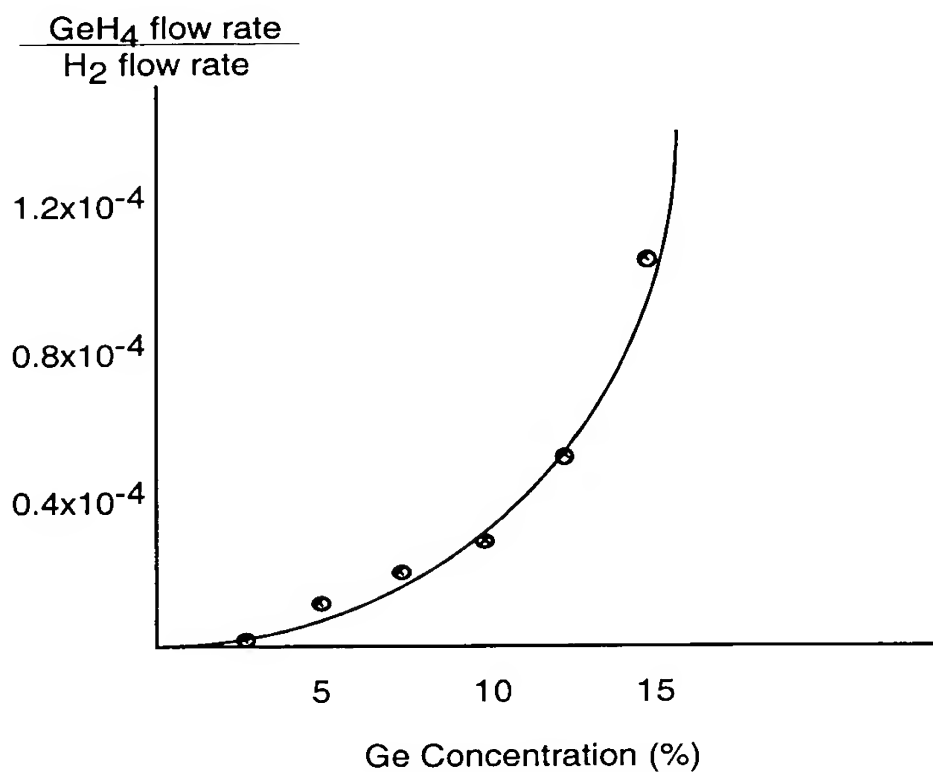


Figure 7A

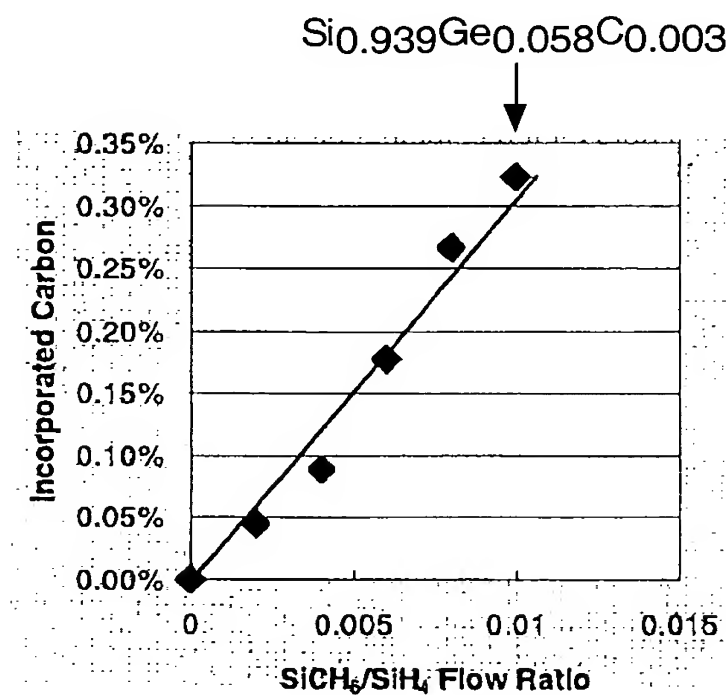


Figure 7B

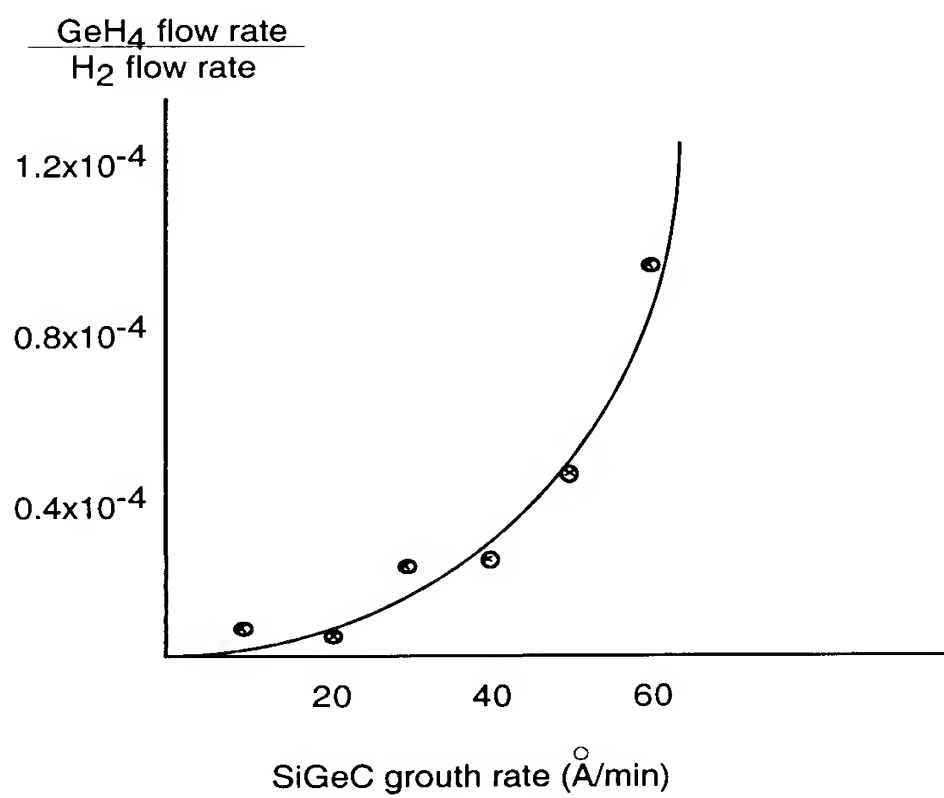
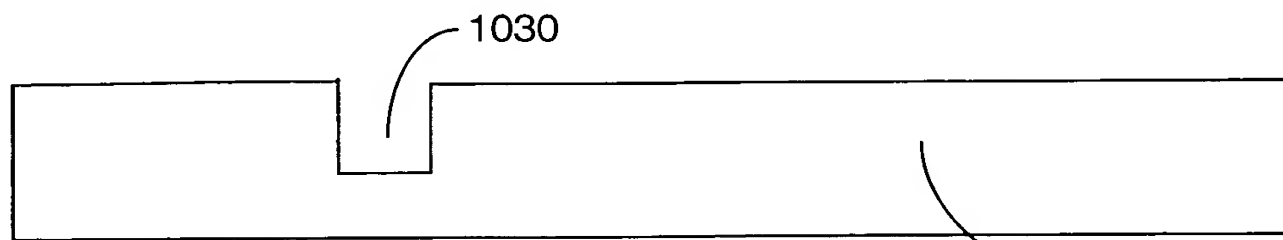
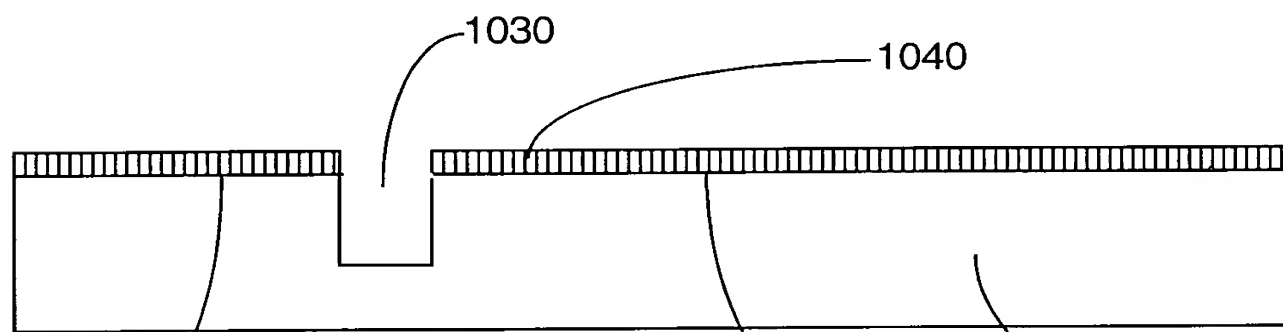


Figure 8

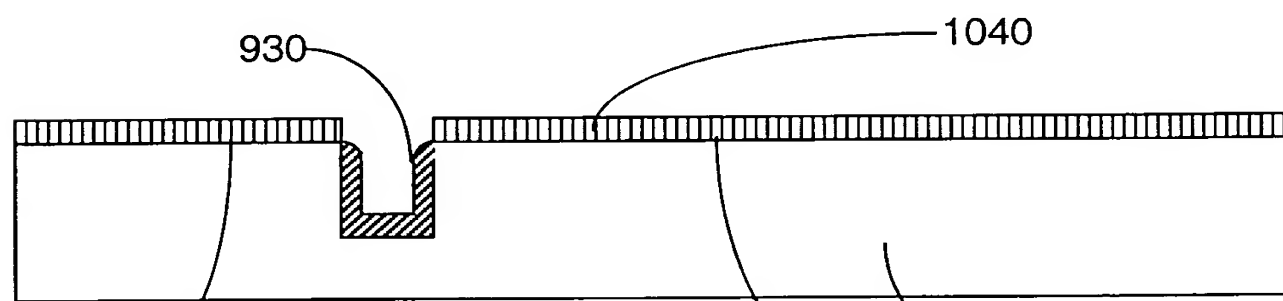
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(a)



(b)



(c)

Figure 9

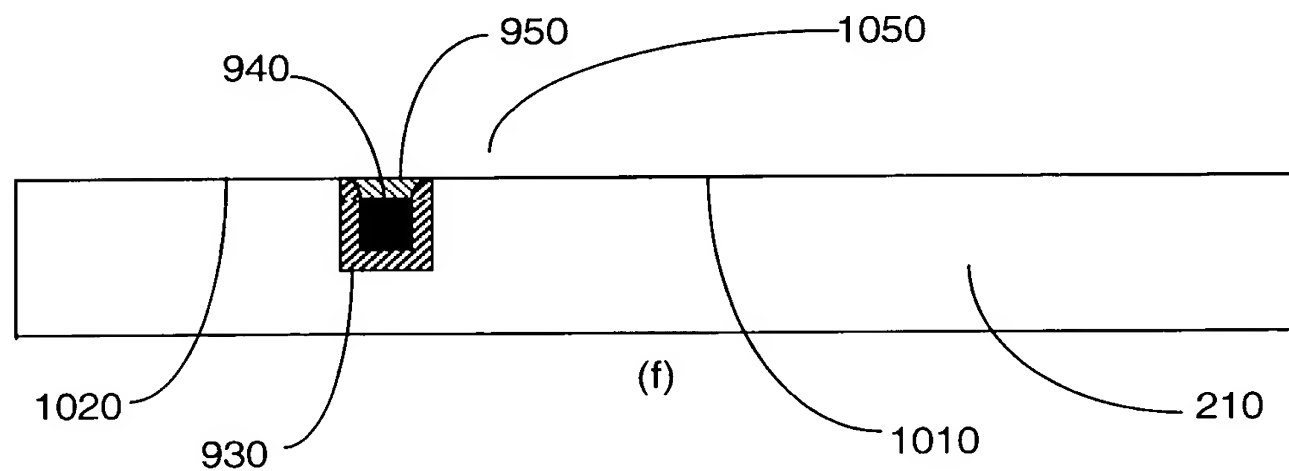
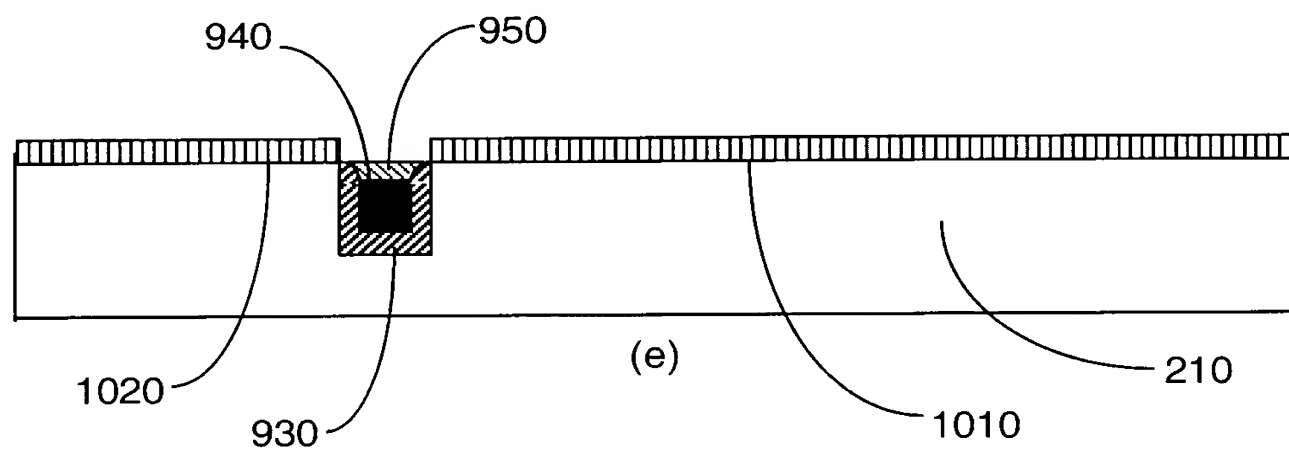
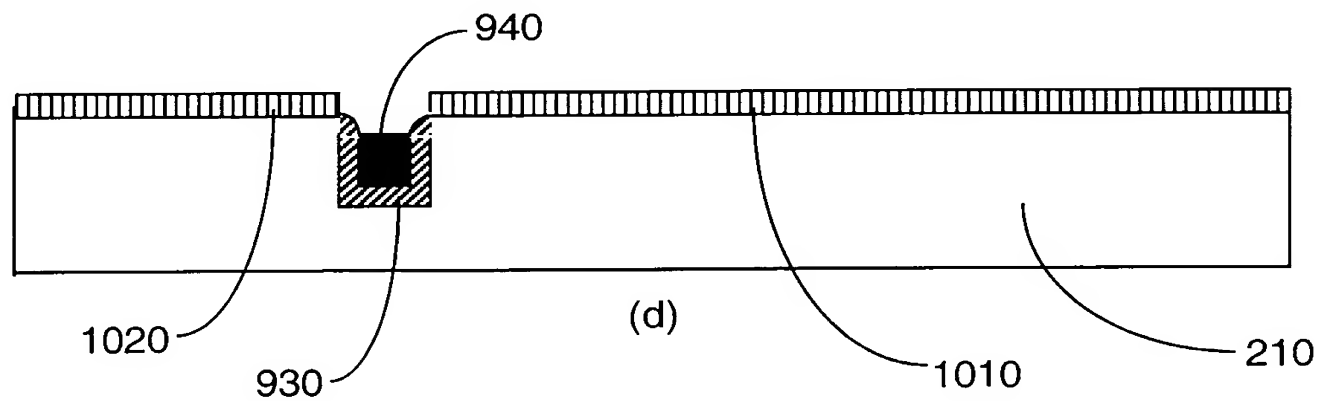


Figure 9

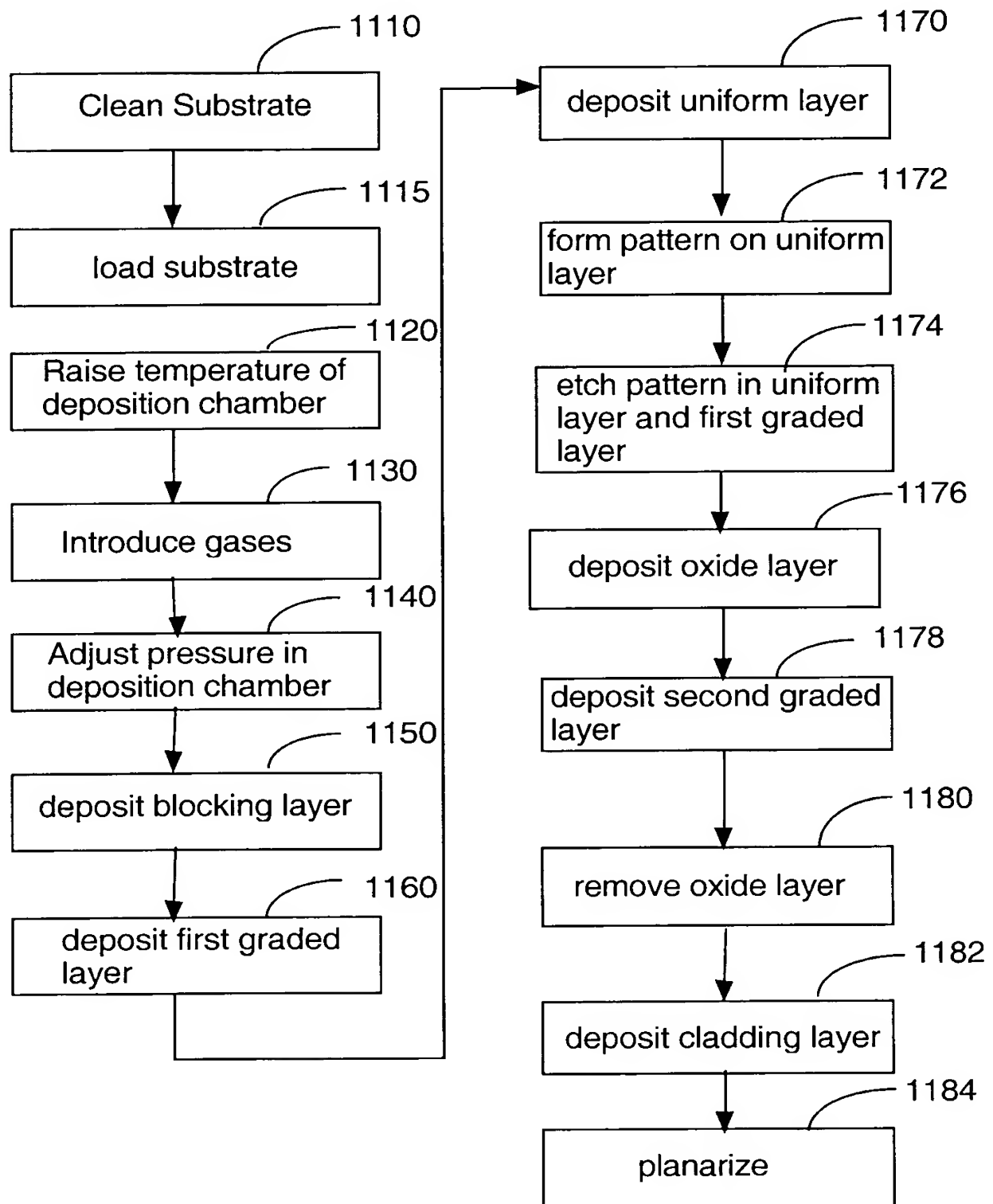


Figure 10

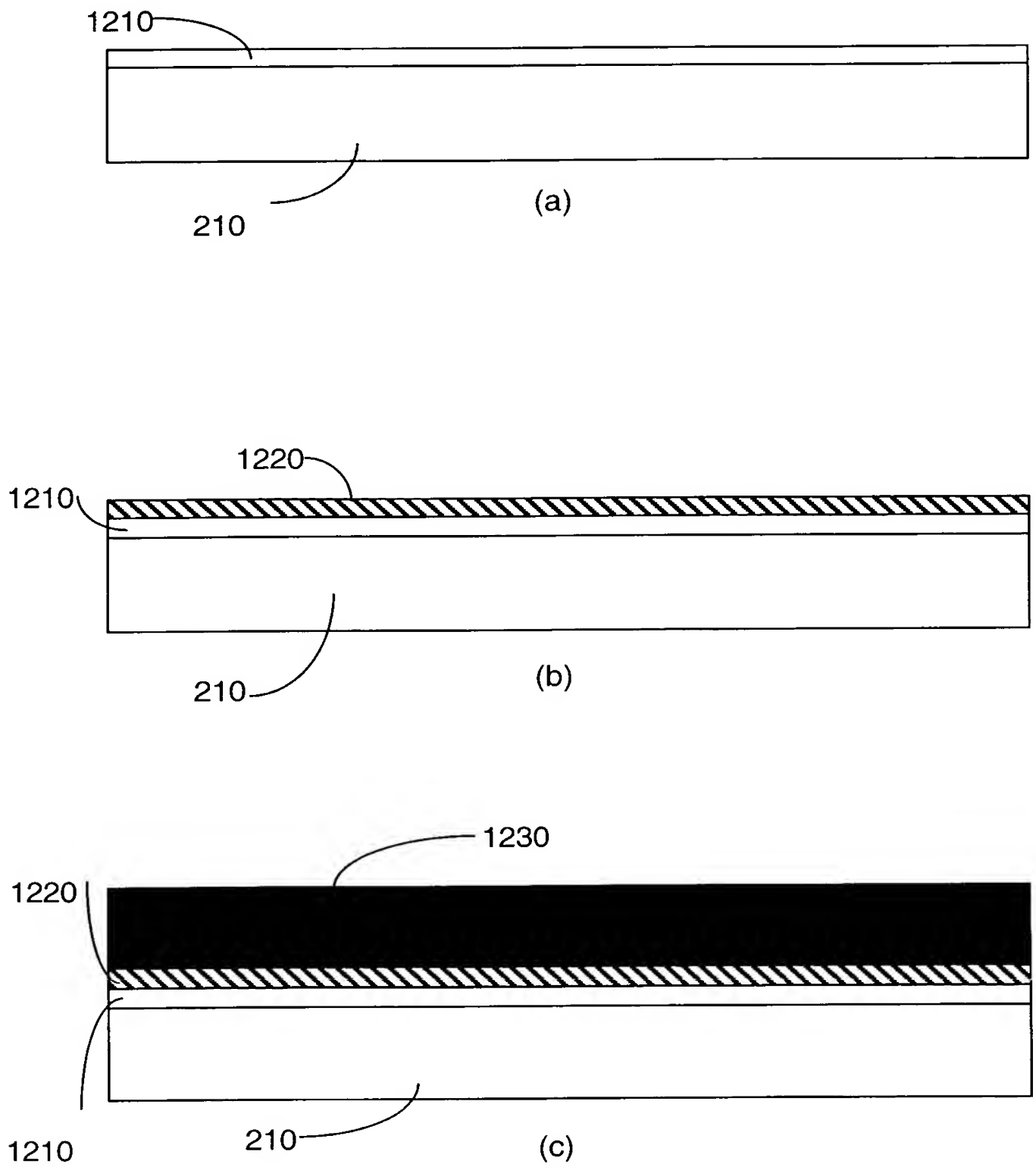


Figure 11

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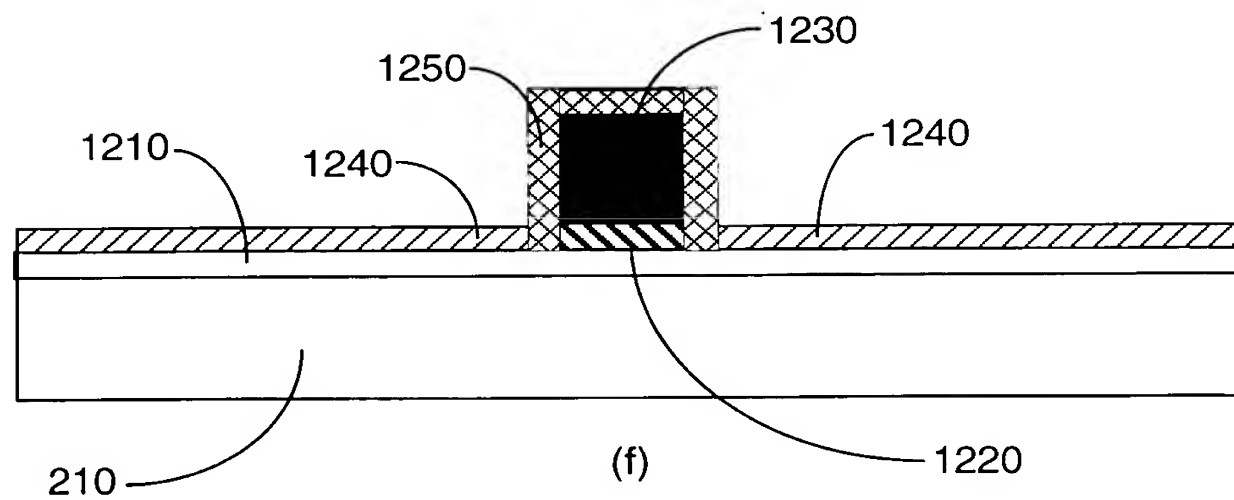
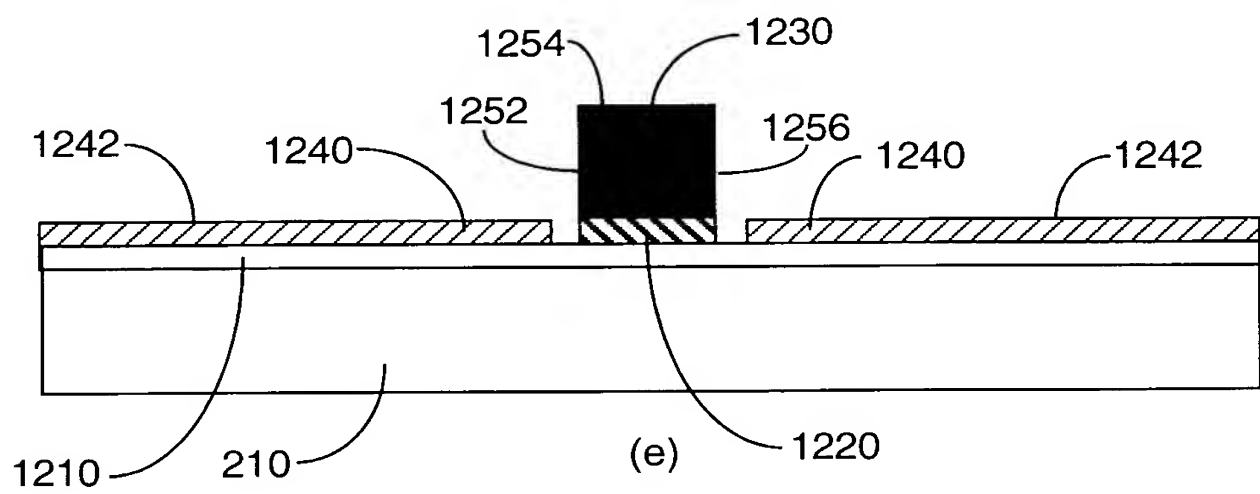
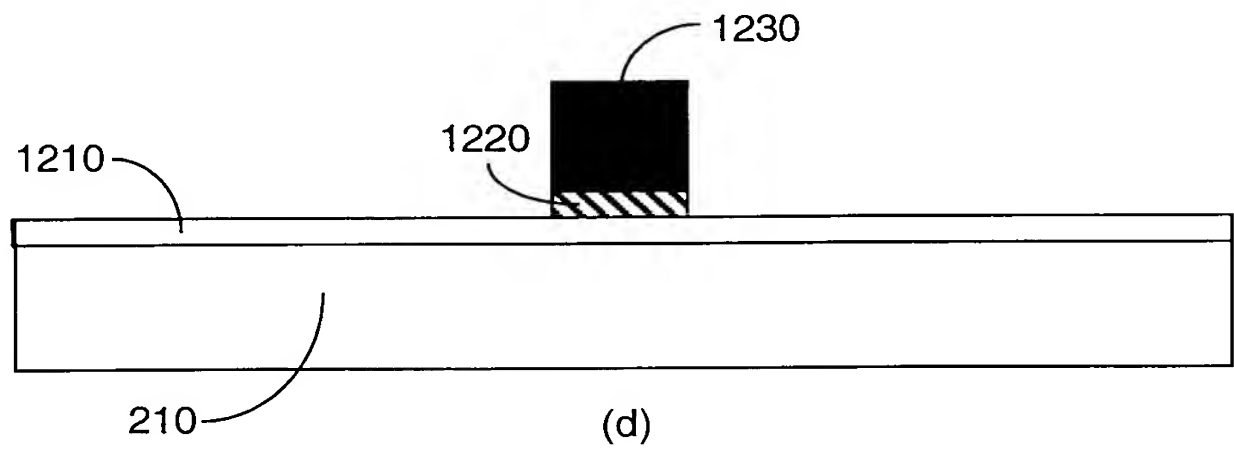


Figure 11

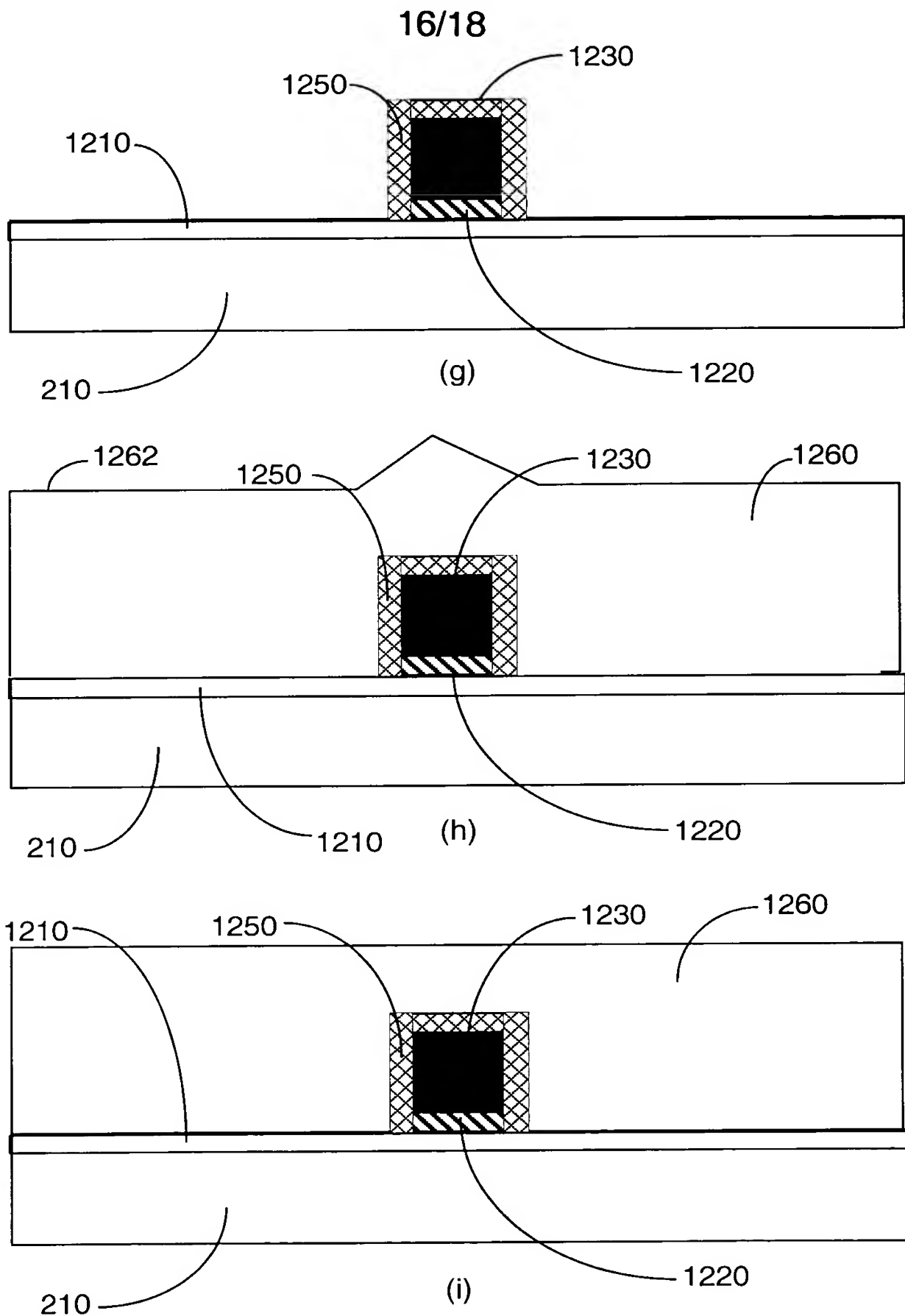


Figure 11

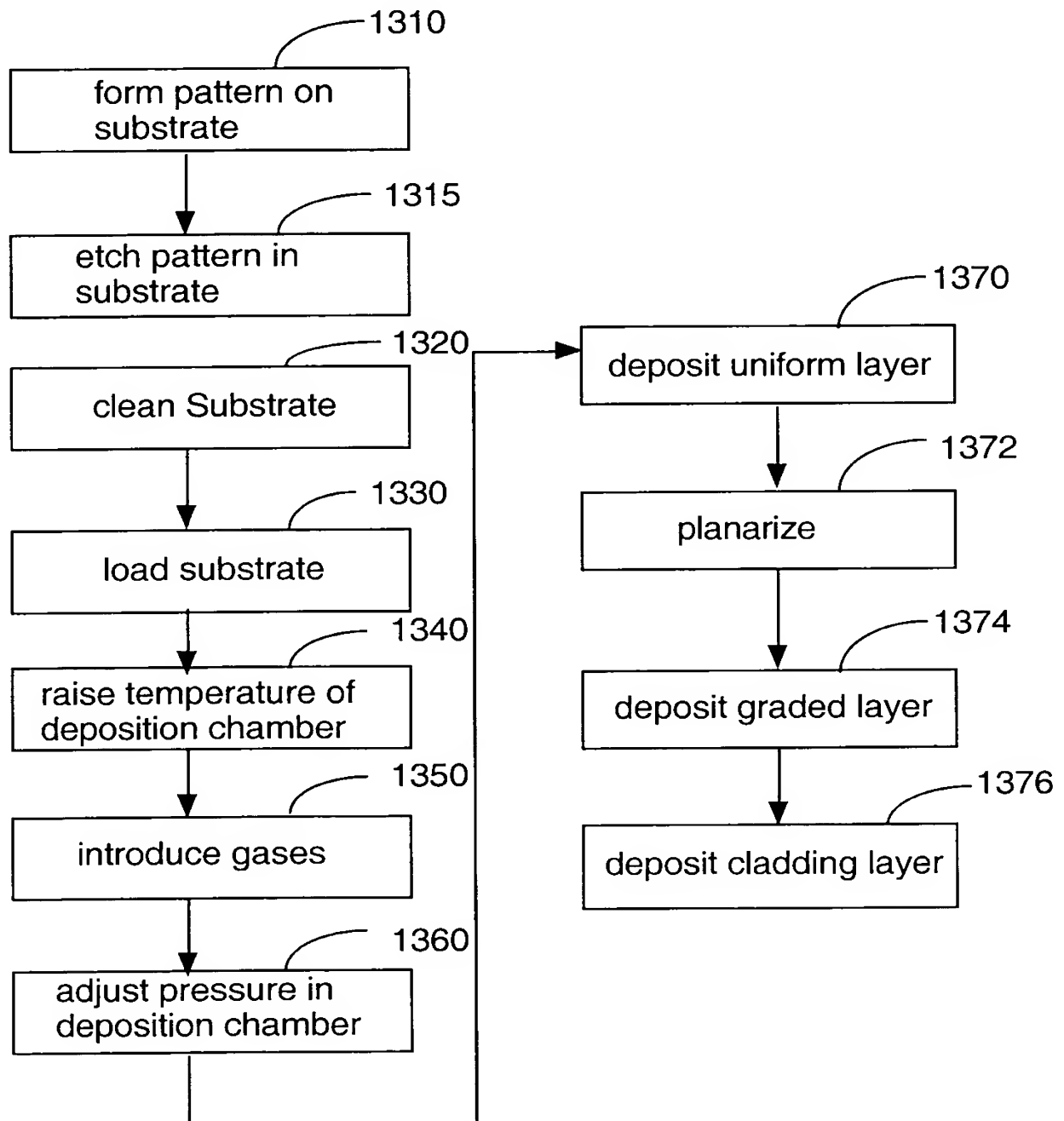


Figure 12

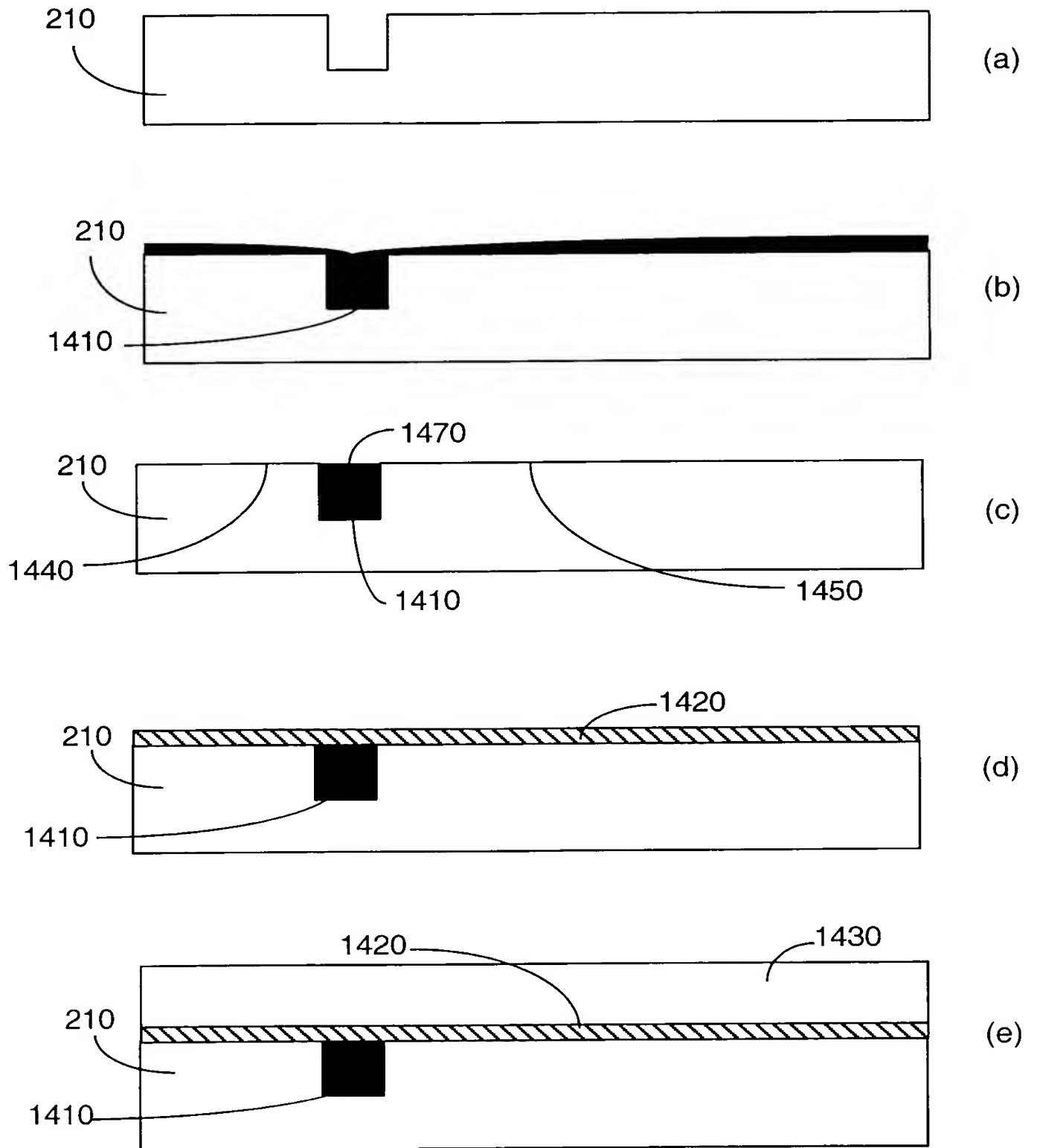


Figure 13